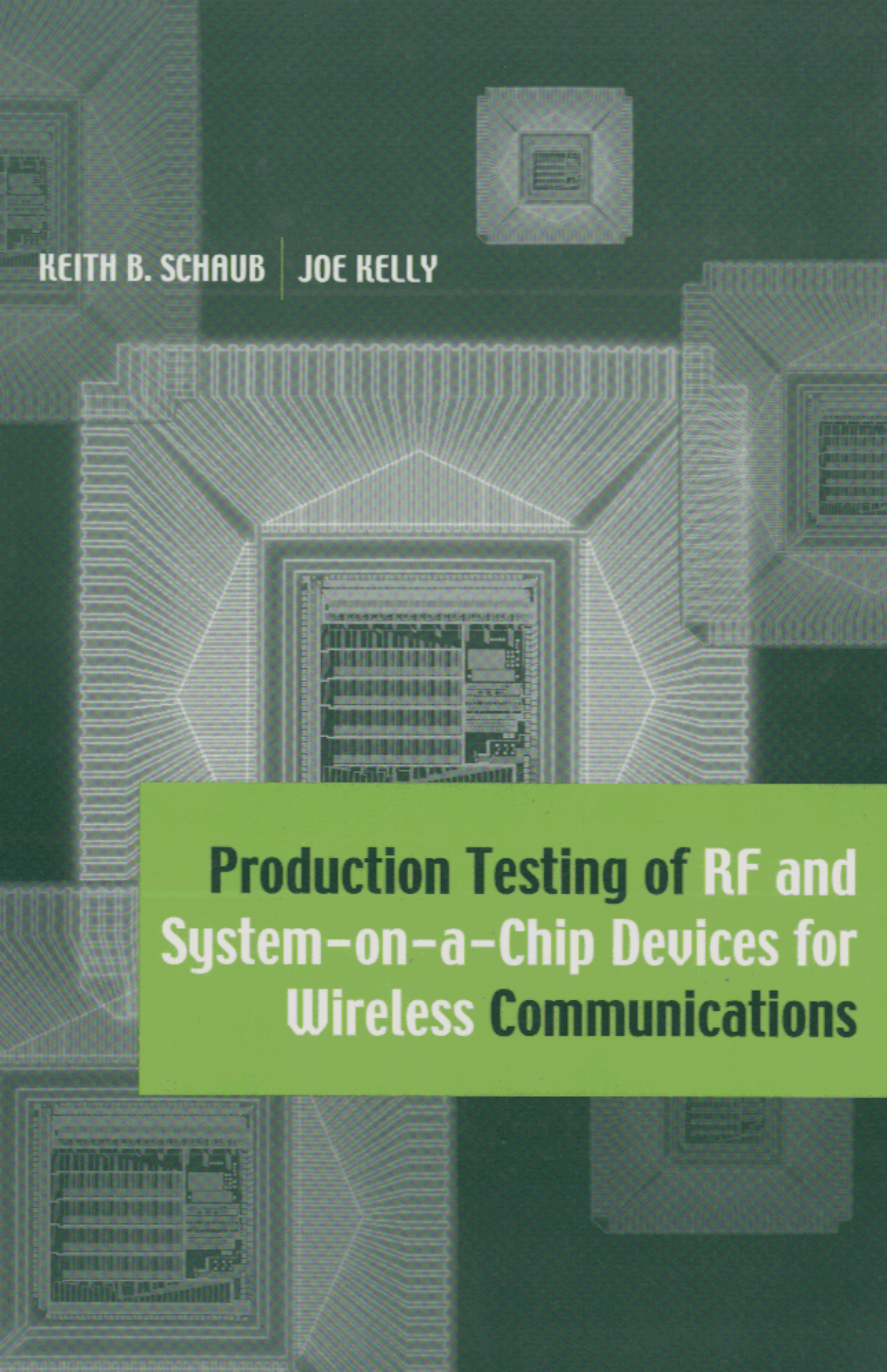

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Production Testing of RF and System-on-a-Chip Devices for Wireless Communications

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